

Serial No.: 10/634,598  
Amendment Dated December 6, 2004  
Reply to Office Action Dated October 20, 2004

**Amendment of Claims:**

This listing of claims will replace all prior versions, and listings of claims in the application:

**Listing of Claims:**

1. (currently amended) An assembly comprising:

a first probe plate including a first hole extending through the first probe plate, the first hole extending through the first probe plate including a first flange area [[capable of]] accommodating a horizontal deflection of a probe; and

a second probe plate positioned below the first probe plate, the second probe plate including a second hole extending through the second probe plate, the second hole extending through the second probe plate including a second flange area [[capable of]] accommodating a horizontal deflection of the probe, wherein

the probe is positioned in the first hole extending through the first probe plate and is positioned in the second hole extending through the second probe plate, the probe [[is capable of ]] performing horizontal movement by deflecting within the first flange area accommodating horizontal deflection of the probe and deflecting within the second flange area accommodating horizontal deflection of the probe.

2 (cancelled). An apparatus comprising:

a printed circuit board including a pad;

a power source applying source voltage to the pad;

a reference input carrying a reference voltage; and

a comparator coupled to the power source and coupled to the reference input, the comparator generating an output in response to the source voltage and in response to the reference voltage.

3 (cancelled). An apparatus as claimed in claim 2, wherein the output indicates a short.

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4 (currently amended). An assembly comprising:

a first probe plate including a first hole extending through the first probe plate, the first hole extending through the first probe plate including a first flange area accommodating a horizontal deflection of a probe; and

a second probe plate positioned below the first probe plate, the second probe plate including a second hole extending through the second probe plate, the second hole extending through the second probe plate including a second flange area accommodating a horizontal deflection of the probe, wherein the probe is positioned in the first hole extending through the first probe plate and is positioned in the second hole extending through the second probe plate, the probe performing horizontal movement by deflecting within the first flange area accommodating horizontal deflection of the probe and deflecting within the second flange area accommodating horizontal deflection of the probe [[An assembly as set forth in claim 1]] and, wherein the horizontal movement is less than or equal to 0.071 inches.

5 (previously added). An assembly as set forth in claim 1, wherein the first hole extending through the first probe plate is a center drilled hole.

6 (previously added). An assembly as set forth in claim 1, wherein the second hole extending through the second probe plate is a center drilled hole.

7 (currently amended). An assembly comprising:

a first probe plate including a first hole extending through the first probe plate, the first hole extending through the first probe plate including a first flange area accommodating a horizontal deflection of a probe; and

a second probe plate positioned below the first probe plate, the second probe plate including a second hole extending through the second probe plate, the second hole extending through the second probe plate including a second flange area accommodating a horizontal deflection of the probe, wherein

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the probe is positioned in the first hole extending through the first probe plate and is positioned in the second hole extending through the second probe plate, the probe performing horizontal movement by deflecting within the first flange area accommodating horizontal deflection of the probe and deflecting within the second flange area accommodating horizontal deflection of the probe [[An assembly as set forth in claim 1]] and, wherein the first probe plate further comprises a ground foil coupled to the first probe plate and providing a pathway to ground.

8 (cancelled). An assembly comprising:

a first probe plate means including a first hole extending through the first probe plate means, the first hole extending through the first probe plate means including a first flange area capable of accommodating a horizontal deflection of a probe means; and

a second probe plate means positioned below the first probe plate means, the second probe plate means including a second hole extending through the second probe plate means, the second hole extending through the second probe plate means including a second flange area capable of accommodating a horizontal deflection of the probe means, wherein the probe means is positioned in the first hole extending through the first probe plate means and is positioned in the second hole extending through the second probe plate means, the probe means is capable of horizontal movement by deflecting within the first flange area accommodating horizontal deflection of the probe means and deflecting within the second flange area accommodating horizontal deflection of the probe means.

9 (currently amended). A method of operating a fixture comprising the steps of:

positioning a first probe plate including a first hole extending through the first probe plate, the first hole extending through the first probe plate including a first flange area capable of accommodating a horizontal deflection of a probe means;

positioning a second probe plate positioned below the first probe plate, the second probe plate including a second hole extending through the second probe plate,

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the second hole extending through the second probe plate including a second flange area capable of accommodating a horizontal deflection of the probe;

inserting the probe through the first hole and the second ~~[[hold]]~~ hole; and

deflecting the probe horizontally thereby producing an offsetting by adjusting the first probe plate horizontally within the first flange and adjusting the probe horizontally within the second flange.

10 (previously added). A method of operating a fixture as set forth in claim 9, wherein the offset is less than 0.071 inches.

11 (previously added). A method of operating a fixture as set forth in claim 9, wherein the further comprises a first end and a second end, the first end is placed in contact with a device in response to adjusting the probe horizontally in the first flange and the second end is placed in contact with a test assembly in response to adjusting the probe horizontally in the second flange.